## Notice of References Cited 10/716,399 Reexamination ABE, TAKASHI Examiner Lam P. Pham 2612 Reexamination ARE TAKASHI Page 1 of 1

Application/Control No.

## U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-6,867,701	03-2005	Lawrence et al.	340/635
*	В	US-5,754,112	05-1998	Novak, Vit F.	340/635
*	С	US-6,107,929	08-2000	Amari, Takeyuki	340/687
*	D	US-5,253,140	10-1993	Inoue et al.	361/728
*	Е	US-6,785,131	08-2004	Ewell et al.	361/686
*	F	US-5,483,229	01-1996	Tamura et al.	340/691.7
*	G	US-2004/0212511	10-2004	Ahrens et al.	340/635
	Н	US-			
	ı	US-			
	J	US-			
	К	US-			
	L	US-			
	М	US-			

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	Z					
	0					
	Р					
	q				25	
	R					
	S					
	Т					

## NON-PATENT DOCUMENTS

$\mathbb{Z}$	•	Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)	
	U		
H			
	V		
	w		
	×		9 - 9 - 7 - 7 - 7 - 7 - 7 - 7 - 7 - 7 -

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

Applicant(s)/Patent Under